RELIABILITY REPORT

FOR

MAX6414UK16+

PLASTIC ENCAPSULATED DEVICES

November 19, 2008

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.

SUNNYVALE, CA 94086

Approved by
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Quality Assurance
Director, Reliability Engineering

Conclusion

The MAX6414UK16+ successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim"s continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim"s quality and reliability standards.

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I. Device Description

A. General

The MAX6412-MAX6420 low-power microprocessor supervisor circuits monitor system voltages from 1.6V to 5V. These devices are designed to assert a reset signal whenever the VCC supply voltage or RESET IN falls below its reset threshold or the manual reset input is asserted. The reset output remains asserted for the reset timeout period after VCC and RESET IN rise above the reset threshold and the manual reset input is deasserted. The reset timeout is externally set by a capacitor to provide more flexibility. The MAX6412/MAX6413/MAX6414 feature fixed thresholds from 1.575V to 5V in approximately 100mV increments and a manual reset input. The MAX6415/MAX6416/MAX6417 are offered with an adjustable reset input that can monitor voltages down to 1.26V and the MAX6418/MAX6419/MAX6420 are offered with one fixed input and one adjustable input to monitor dual-voltage systems. The MAX6412/MAX6415/MAX6418 have an active-low, push-pull reset output. The MAX6413/MAX6416/MAX6419 have an active-high, push-pull reset output and the MAX6414/MAX6417/MAX6420 have an active-low, open-drain reset output. All of these devices are offered in a SOT23-5 package and are fully specified from -40°C to +125°C.

II. Manufacturing Information

A. Description/Function:	Low-Power, Single/Dual-Voltage µP Reset Circuits with Capacitor-Adjustable Reset Timeout Delay
B. Process:	B8
C. Number of Device Transistors:	0
D. Fabrication Location:	Texas
E. Assembly Location:	Carsm Malaysia, ISPL Philippines, Hana Thailand, UTL Thailand, Unisem Malaysia
F. Date of Initial Production:	January 26, 2002

III. Packaging Information

A. Package Type:	5-pin SOT23
B. Lead Frame:	Copper
C. Lead Finish:	100% matte Tin
D. Die Attach:	Conductive Epoxy
E. Bondwire:	Gold (1 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-1601-0178
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	324.3°C/W
K. Single Layer Theta Jc:	82°C/W

IV. Die Information

A. Dimensions:	36 X 36 mils
B. Passivation:	Si_3N_4/SiO_2 (Silicon nitride/ Silicon dioxide
C. Interconnect:	Aluminum/Si (Si = 1%)
D. Backside Metallization:	None
E. Minimum Metal Width:	0.8 microns (as drawn)
F. Minimum Metal Spacing:	0.8 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO_2
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts:	Ken Wendel (Director, Reliability Engineering) Bryan Preeshl (Managing Director of QA)
B. Outgoing Inspection Level:	0.1% for all electrical parameters guaranteed by the Datasheet. 0.1% For all Visual Defects.
C. Observed Outgoing Defect Rate:	< 50 ppm
D. Sampling Plan:	Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are pending. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{MTTF} = \frac{1.83}{192 \times 4340 \times 135 \times 2}$$ (Chi square value for MTTF upper limit)

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$\lambda = 8.0 \times 10^{-9}$

$\lambda = 8.0$ F.I.T. (60% confidence level @ 25°C)

This low failure rate represents data collected from Maxim"s reliability monitor program. In addition to routine production Burn-In, Maxim pulls a sample from every fabrication process three times per week and subjects it to an extended Burn-In prior to shipment to ensure its reliability. The reliability control level for each lot to be shipped as standard product is 59 F.I.T. at a 60% confidence level, which equates to 3 failures in an 80 piece sample. Maxim performs failure analysis on any lot that exceeds this reliability control level. Attached Burn-In Schematic (Spec. # 06-5889) shows the static Burn-In circuit. Maxim also performs quarterly 1000 hour life test monitors. This data is published in the Product Reliability Report (RR-1N). Current monitor data for the S4 Process results in a FIT Rate of 0.09 @ 25C and 1.61 @ 55C (0.8 eV, 60% UCL)

B. Moisture Resistance Tests

The industry standard 85°C/85%RH or HAST testing is monitored per device process once a quarter.

C. E.S.D. and Latch-Up Testing

The MS60-2 die type has been found to have all pins able to withstand a HBM transient pulse of +/-1000V per JEDEC JESD22-A114-D and a CDM transient pulse of +/-750V. Latch-Up testing has shown that this device withstands a current of +/-250 mA.

Table 1
Reliability Evaluation Test Results

MAX6414UK16+

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES
Static Life Test (Note 1)				
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	135	0
Moisture Testing (Note 2)				
85/85	Ta = 85°C RH = 85% Biased Time = 1000hrs.	DC Parameters & functionality	77	0
Mechanical Stress (Note 2)				
Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters & functionality	77	0

Note 1: Life Test Data may represent plastic DIP qualification lots.
Note 2: Generic Package/Process data